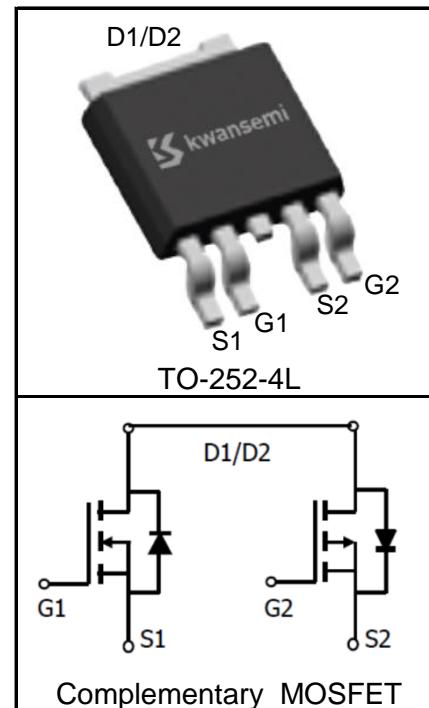


Features

- N-Channel
30V/25A,
 $R_{DS\ (ON)} = 15m\Omega$ (Typ.) @ $V_{GS}=10V$
- $R_{DS\ (ON)} = 20m\Omega$ (Typ.) @ $V_{GS}=4.5V$
- P-Channel
-30V/-28A,
 $R_{DS\ (ON)} = 18m\Omega$ (Typ.) @ $V_{GS}=-10V$
- $R_{DS\ (ON)} = 28m\Omega$ (Typ.) @ $V_{GS}=-4.5V$
- Very low on-resistance
- Fast Switching

Pin Description



Applications

- DC Fan
- Motor Drive Applications



Halogen-Free

Absolute Maximum Ratings

Symbol	Parameter	N-Channel	P-Channel	Unit
Common Ratings ($T_A=25^\circ C$ Unless Otherwise Noted)				
V_{DSS}	Drain-Source Voltage	30	-30	V
V_{GSS}	Gate-Source Voltage	± 20	± 20	
T_J	Maximum Junction Temperature	150	150	$^\circ C$
T_{STG}	Storage Temperature Range	-55 to 150	-55 to 150	$^\circ C$
I_S	Diode Continuous Forward Current	$T_C=25^\circ C$	25	-28
Mounted on Large Heat Sink				
$I_{DP}^{(1)}$	300 μs Pulse Drain Current Tested	$T_C=25^\circ C$	100	-112
$I_D^{(2)}$	Continuous Drain Current($V_{GS}=\pm 10V$)	$T_C=25^\circ C$	25	-28
		$T_C=100^\circ C$	16	-18
P_D	Maximum Power Dissipation	$T_C=25^\circ C$	22	33
		$T_C=100^\circ C$	9	13
$R_{\theta JC}$	Thermal Resistance-Junction to Case	5.6	3.8	$^\circ C/W$
$R_{\theta JA}^{(3)}$	Thermal Resistance-Junction to Ambient	100	100	$^\circ C/W$
Drain-Source Avalanche Ratings				
$E_{AS}^{(4)}$	Avalanche Energy, Single Pulsed	9	20	mJ

Electrical Characteristics (T_C=25°C Unless Otherwise Noted)

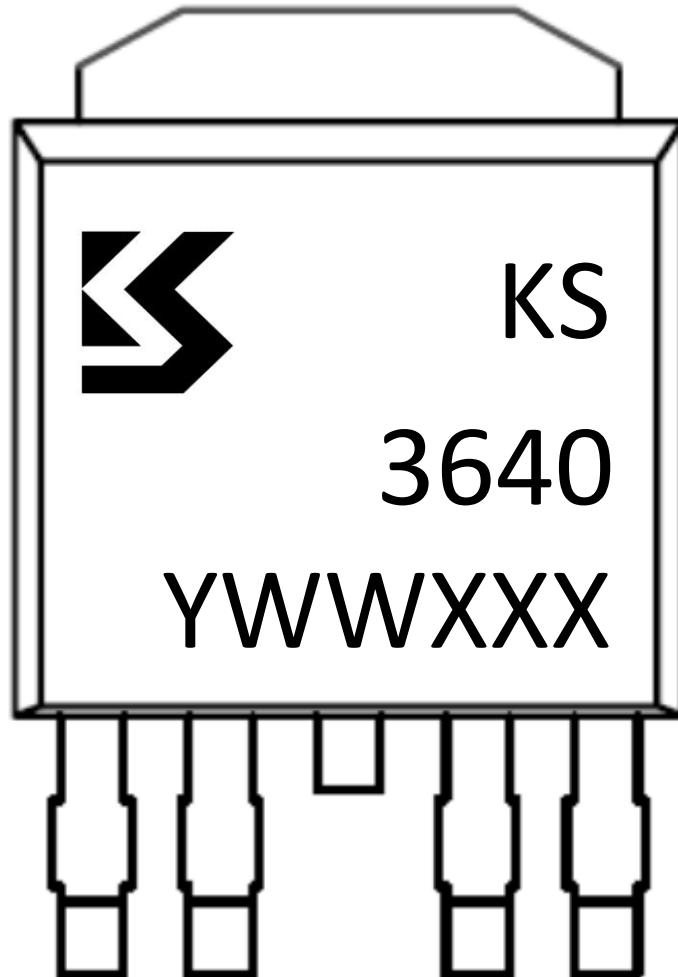
Symbol	Parameter	Test Condition	KS3640DB4			Unit
			Min.	Typ.	Max.	
Static Characteristics						
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V, I _{DS} =250μA	N	30		V
		V _{GS} =0V, I _{DS} =-250μA	P	-30		
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} =30V, V _{GS} =0V	N			1
		T _J =125°C				30
		V _{DS} =-30V, V _{GS} =0V	P			-1
		T _J =125°C				-30
V _{GS(th)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _{DS} =250μA	N	1.1	1.8	2.3
		V _{DS} =V _{GS} , I _{DS} =-250μA	P	-1.1	-1.5	-2.3
I _{GSS}	Gate Leakage Current	V _{GS} =±20V, V _{DS} =0V	N			±100
		V _{GS} =±20V, V _{DS} =0V	P			±100
R _{DS(ON)} ^⑤	Drain-Source On-state Resistance	V _{GS} =10V, I _{DS} =10A	N		15	20
		V _{GS} =-10V, I _{DS} =-10A	P		18	25
		V _{GS} =4.5V, I _{DS} =6A	N		20	28
		V _{GS} =-4.5V, I _{DS} =-6A	P		28	35
Diode Characteristics						
V _{SD} ^⑤	Diode Forward Voltage	I _{SD} =10A, V _{GS} =0V	N		0.86	1.2
		I _{SD} =-10A, V _{GS} =0V	P		-0.86	-1.2
t _{rr}	Reverse Recovery Time	N-Channel I _{SD} =10A, dI _{SD} /dt=100A/μs	N		10	
			P		16	
Q _{rr}	Reverse Recovery Charge	P-Channel I _{SD} =-10A, dI _{SD} /dt=100A/μs	N		14	
			P		27	
Dynamic Characteristics^⑥						
R _G	Gate Resistance	V _{GS} =0V, V _{DS} =0V, F=1MHz	N		1.8	
			P		4.5	
C _{iss}	Input Capacitance	N-Channel V _{GS} =0V, V _{DS} =15V, Frequency=1.0MHz	N		460	
			P		1190	
C _{oss}	Output Capacitance	P-Channel V _{GS} =0V, V _{DS} =-15V, Frequency=1.0MHz	N		70	
			P		175	
C _{rss}	Reverse Transfer Capacitance		N		45	
			P		120	

Electrical Characteristics ($T_C=25^\circ\text{C}$ Unless Otherwise Noted)

Symbol	Parameter	Test Condition	KS3640DB4			Unit			
			Min.	Typ.	Max.				
Dynamic Characteristics^⑥									
$t_{d(\text{ON})}$	Turn-on Delay Time	N-Channel $V_{DD}=15V$, $I_{DS}=10A$, $V_{GEN}=10V$, $R_G=3\Omega$	N	8		ns			
			P	14					
			N	12					
			P	25					
	Turn-off Delay Time	P-Channel $V_{DD}=-15V$, $I_{DS}=-10A$, $V_{GEN}=-10V$, $R_G=3\Omega$	N	20					
			P	34					
			N	9					
			P	15					
Gate Charge Characteristics^⑥									
Q_g	Total Gate Charge	N-Channel $V_{DS}=15V$, $V_{GS}=10V$, $I_{DS}=10A$	N	11		nC			
			P	24					
			N	3.1					
			P	5.2					
Q_{gs}	Gate-Source Charge	P-Channel $V_{DS}=-15V$, $V_{GS}=-10V$, $I_{DS}=-10A$	N	4.1		nC			
			P	7.3					
Notes:									
①Pulse width limited by safe operating area.									
②Calculated continuous current based on maximum allowable junction temperature.									
③When mounted on 1 inch square copper board, $t \leq 10\text{sec}$. The value in any given application depends on the user's specific board design.									
④Limited by $T_{J\max}$. Starting $T_J = 25^\circ\text{C}$, N Channel: $L = 0.5\text{mH}$, $R_G = 25\Omega$, $I_{AS} = 6\text{A}$, $V_{GS} = 10\text{V}$, P-Channel: $L = 0.5\text{mH}$, $R_G = 25\Omega$, $I_{AS} = -9\text{A}$, $V_{GS} = -10\text{V}$, Part not recommended for use above this value.									
⑤Pulse test; Pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$.									
⑥Guaranteed by design, not subject to production testing.									

Ordering and Marking Information

Device	Package	Packaging	Quantity	Reel Size	Tape width
KS3640DB4	TO-252-4L	Tape&Reel	2500	13"	16mm

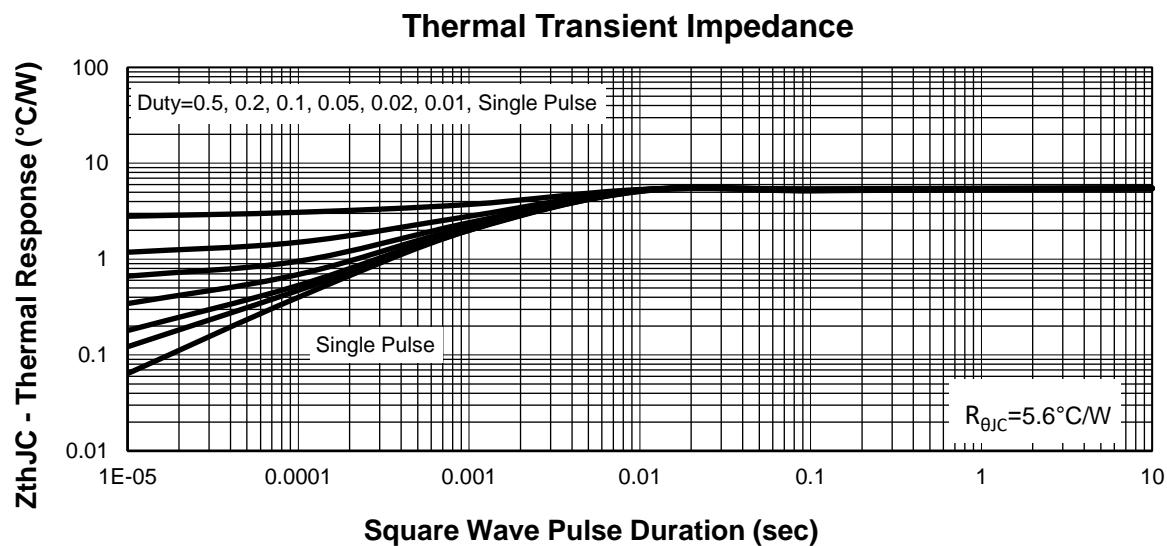
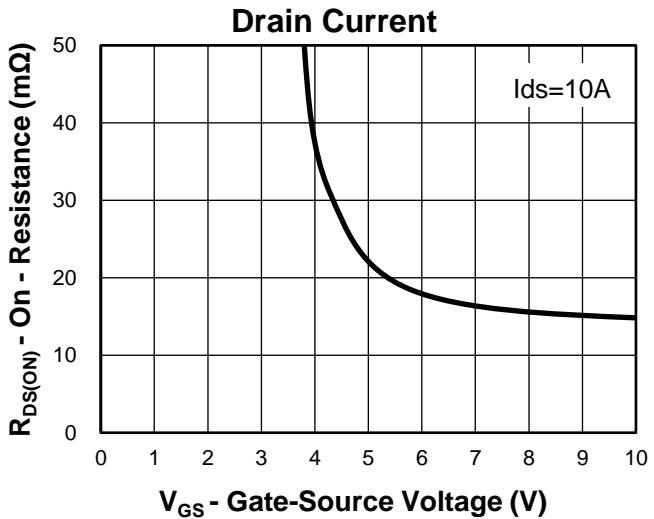
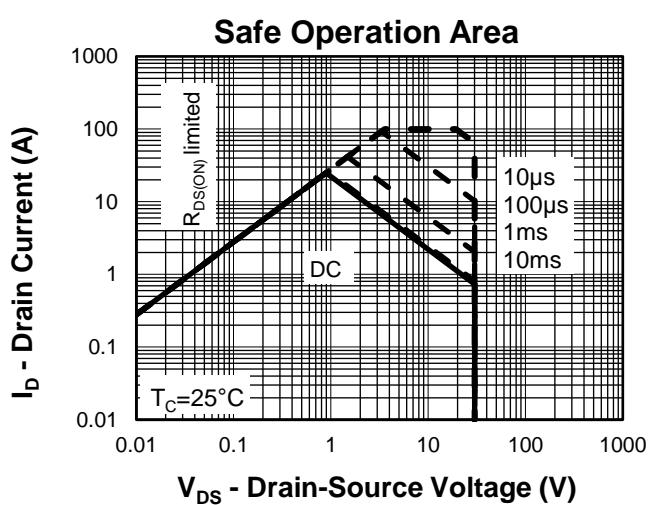
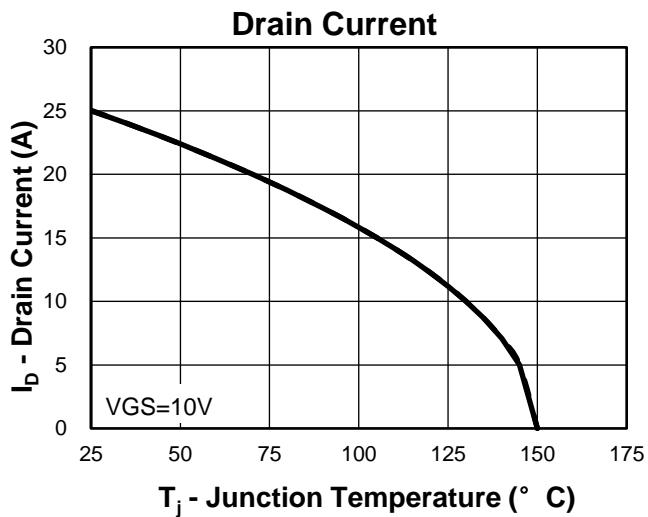
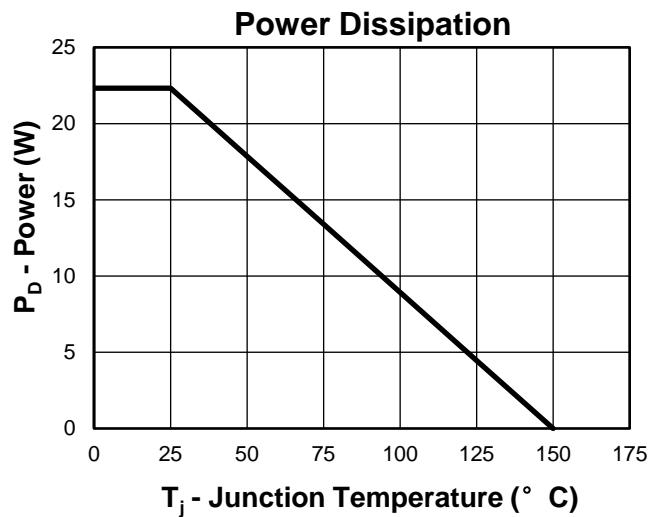


Y =Year,2017-A,2018-B,etc.

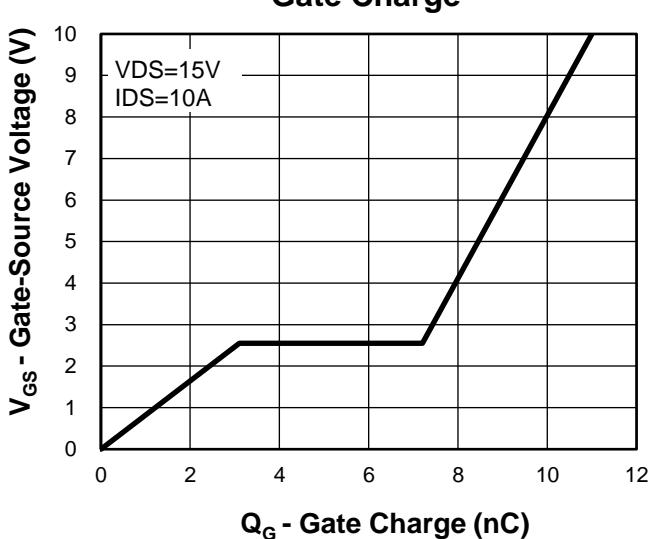
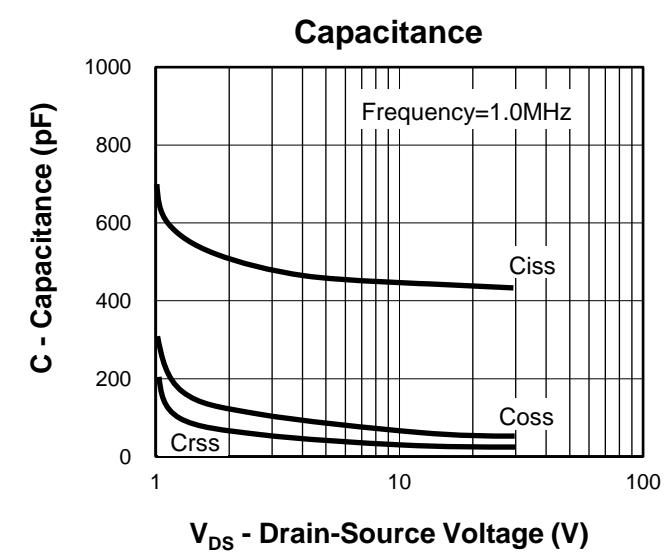
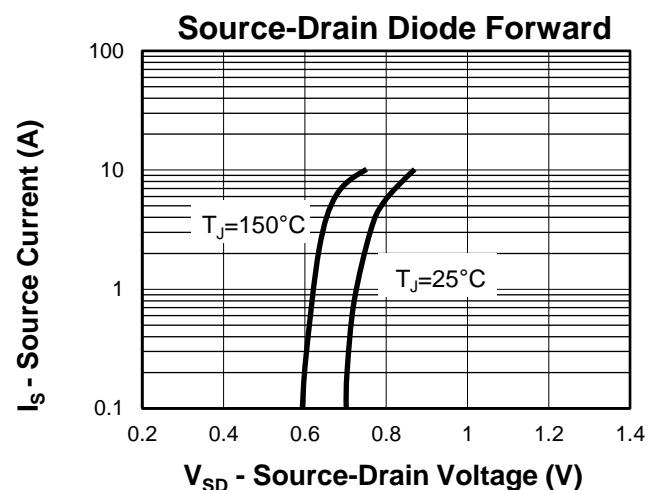
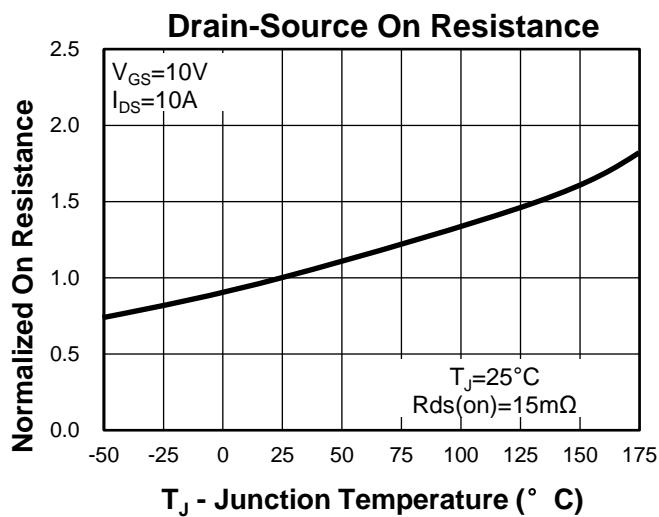
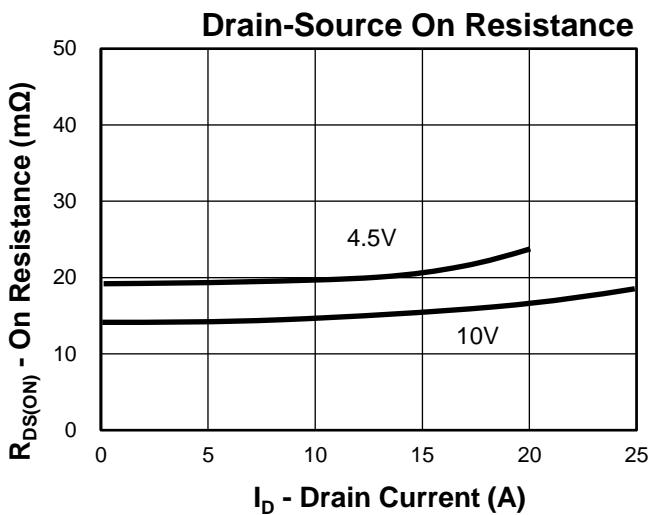
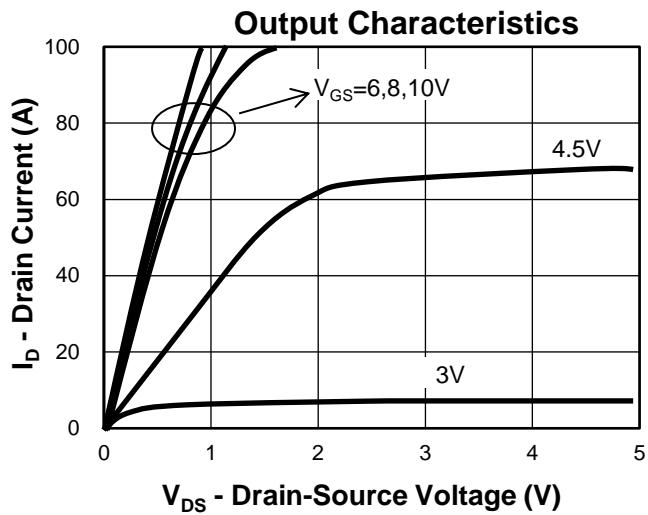
WW =Week.

XXX =Lot number.

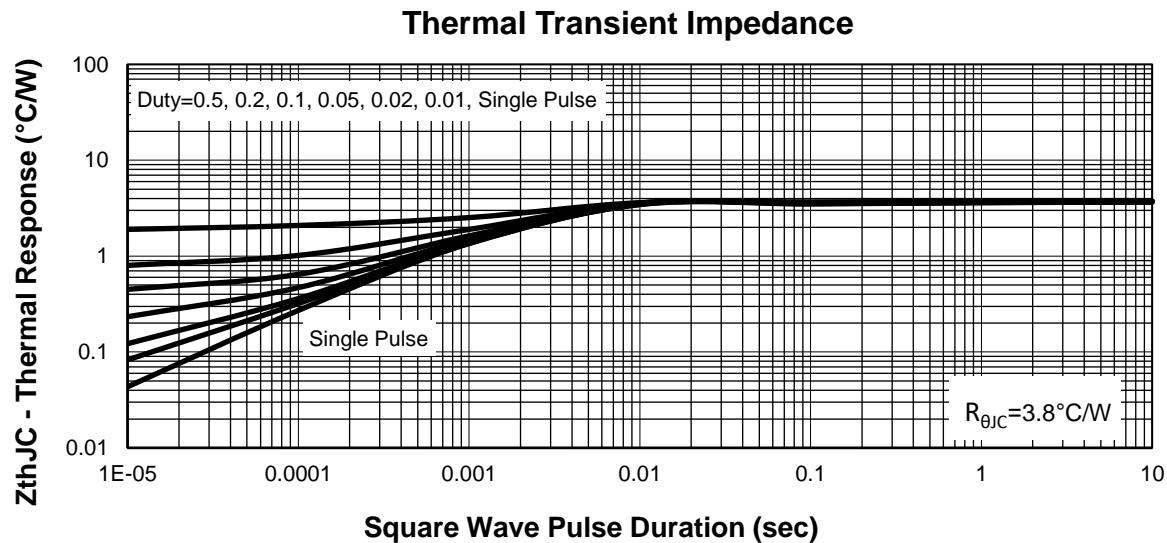
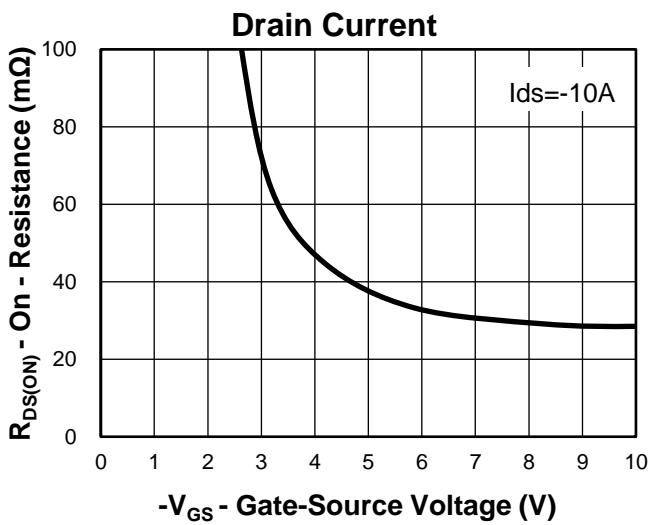
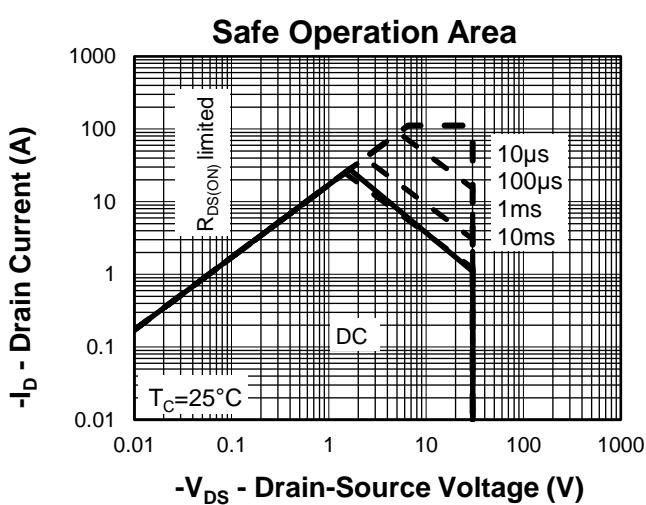
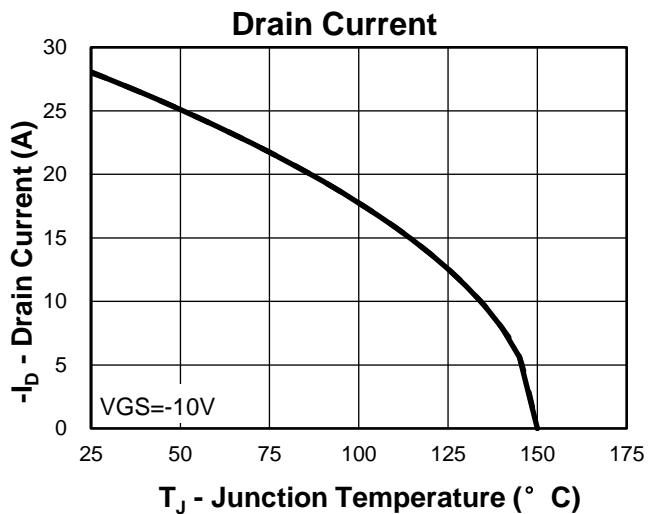
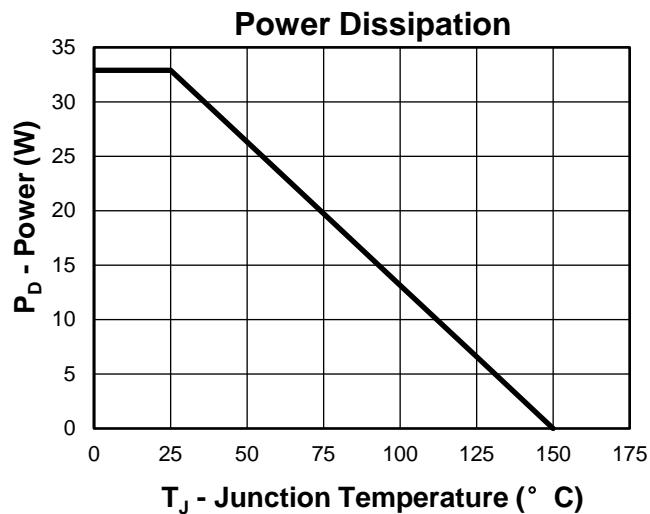
Typical Characteristics(N-Channel)



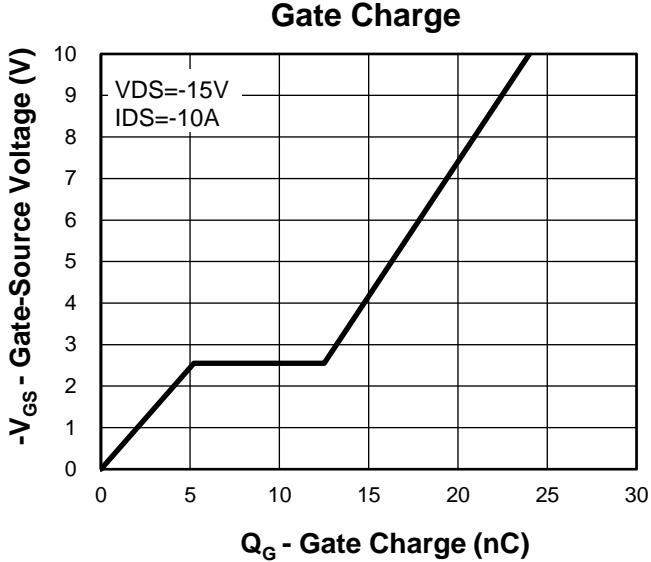
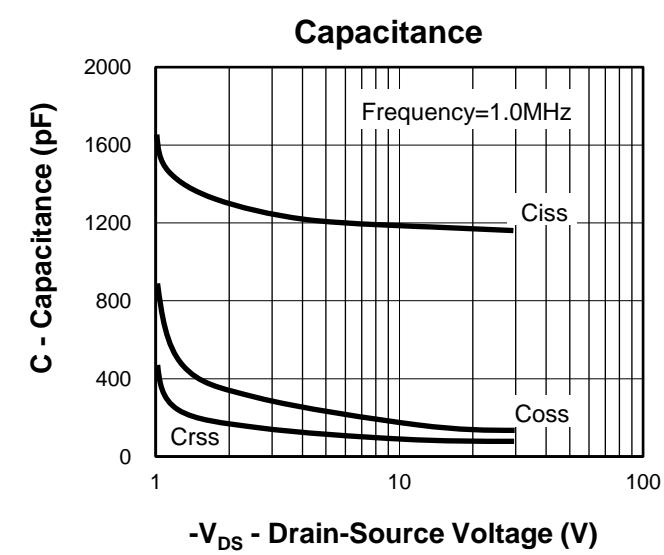
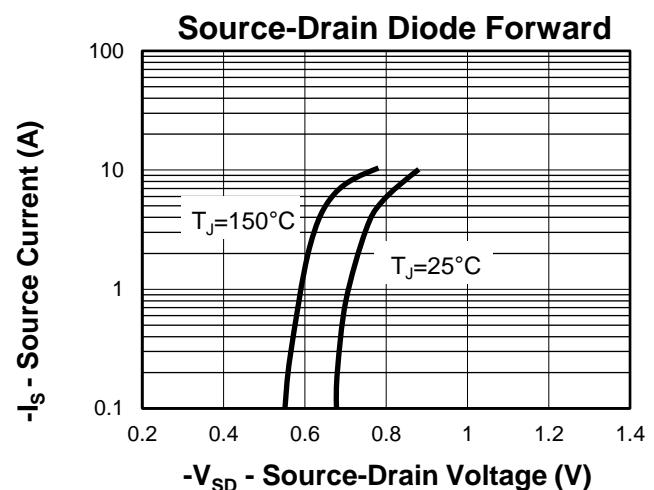
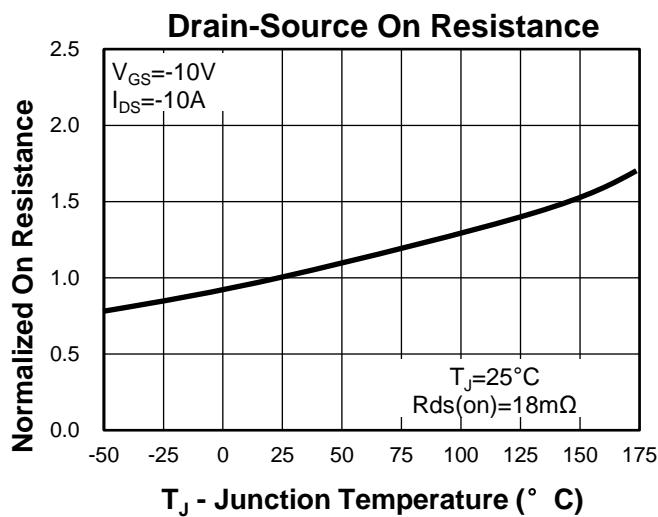
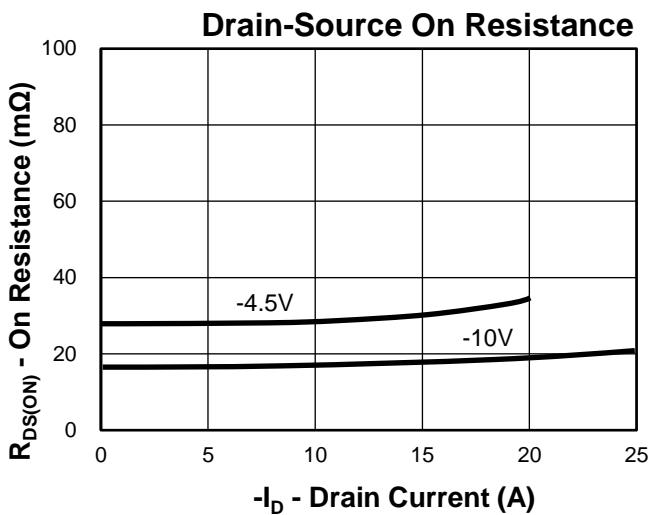
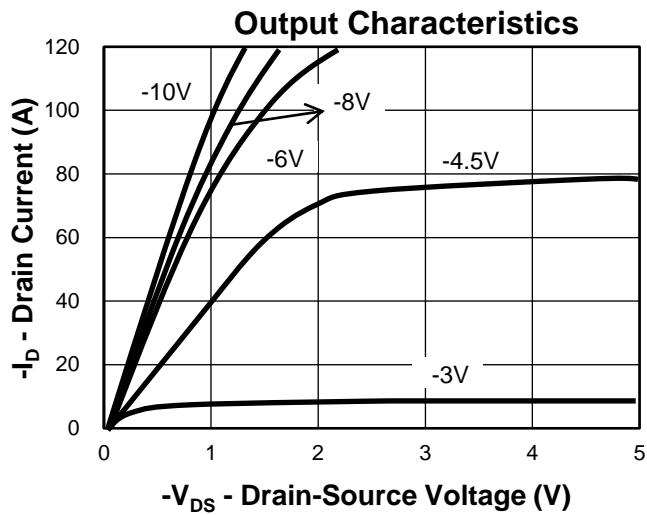
Typical Characteristics(N-Channel)

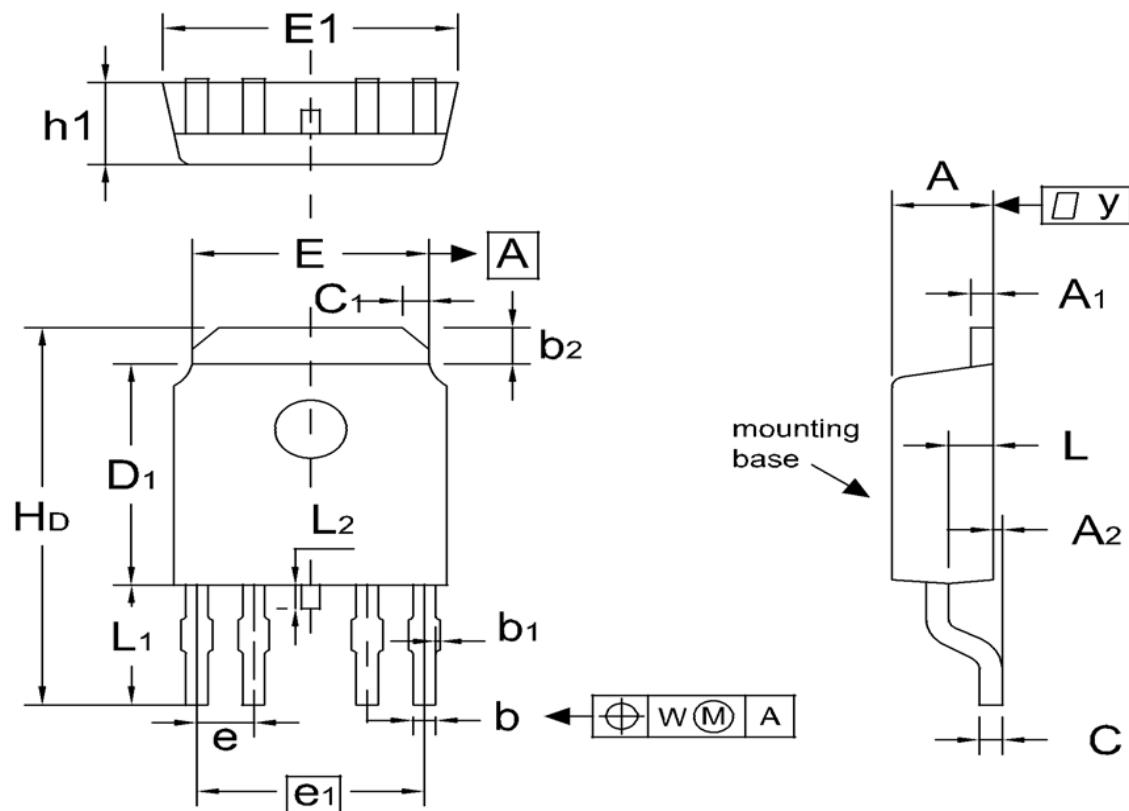


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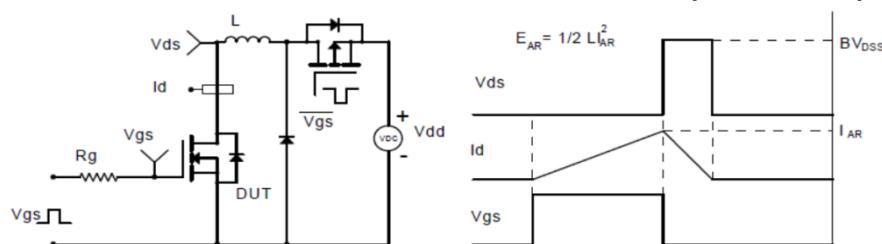
Typical Characteristics(P-Channel)



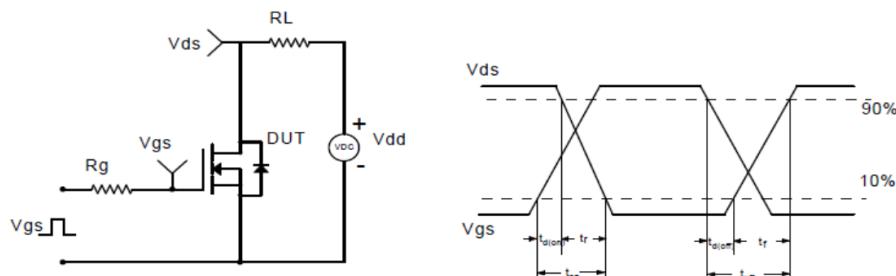
Package Information
TO-252-4L


SYMBOL	MM			INCH		
	MIN	NOM	MAX	MIN	NOM	MAX
A	2.190	2.285	2.380	0.086	0.090	0.094
A1	0.460	0.650	0.880	0.018	0.026	0.035
A2	--	--	0.127	--	--	0.005
b	0.510	0.610	0.710	0.020	0.024	0.028
b1	--	--	0.100	--	--	0.004
b2	0.890	1.080	1.270	0.035	0.043	0.050
C	0.460	0.530	0.600	0.018	0.021	0.024
C1	0.400	0.600	0.800	0.016	0.024	0.031
D1	5.970	6.095	6.220	0.235	0.240	0.245
E	4.320	4.890	5.460	0.170	0.193	0.215
E1	6.350	6.540	6.730	0.250	0.257	0.265
e		1.270 BSC			0.05 BSC	
e1		5.080 BSC			0.20 BSC	
H _D	9.60	10.00	10.40	0.378	0.39	0.409
h1	2.19	2.29	2.38	0.086	0.09	0.094
L	0.80	1.00	1.20	0.031	0.04	0.047
L1	2.60	2.90	3.20	0.102	0.11	0.126
L2	0.350	0.650	0.950	0.014	0.026	0.037

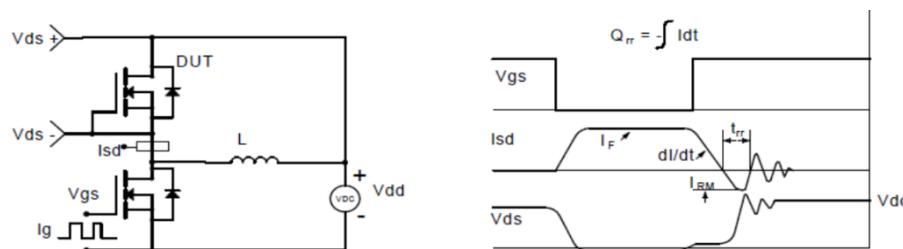
Avalanche Test Circuit and Waveforms(N-Channel)



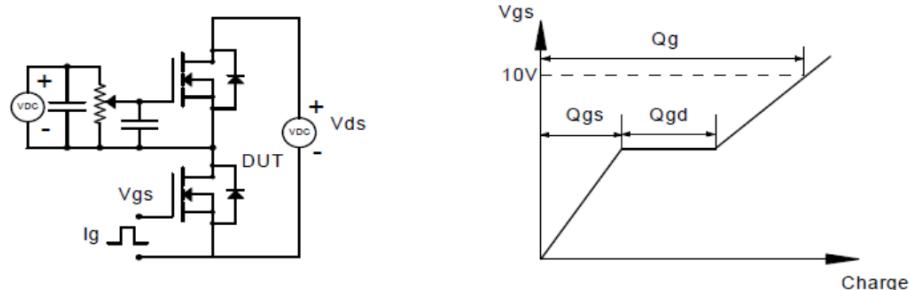
Switching Time Test Circuit and Waveforms(N-Channel)



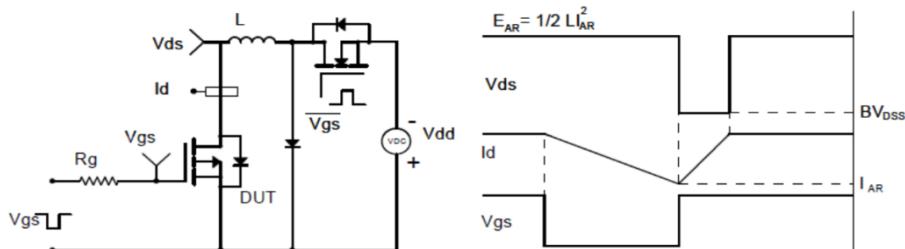
Diode Recovery Test Circuit and Waveforms(N-Channel)



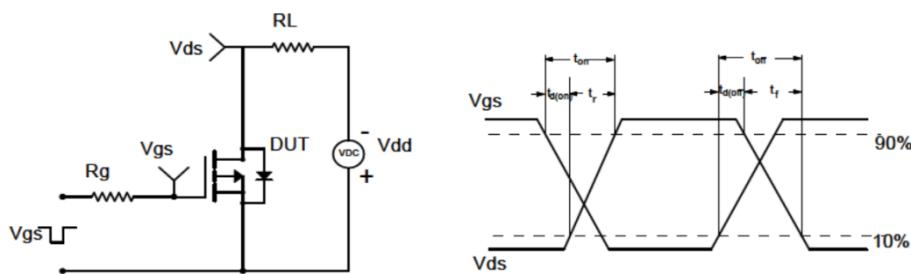
Gate Charge Test Circuit and Waveform(N-Channel)



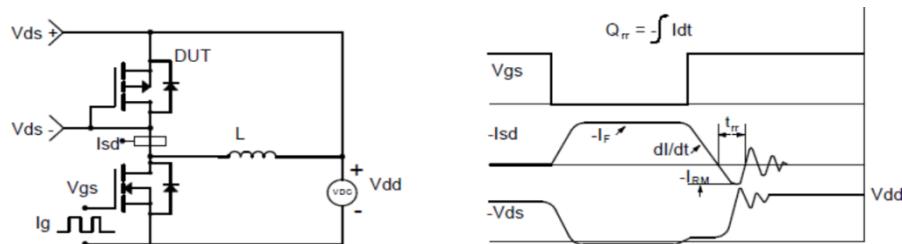
Avalanche Test Circuit and Waveforms(P-Channel)



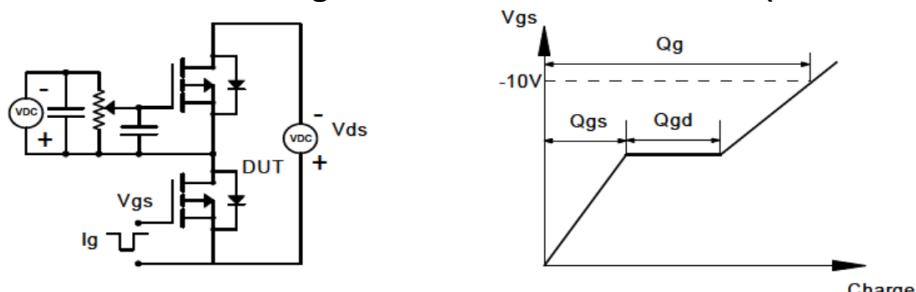
Switching Time Test Circuit and Waveforms(P-Channel)



Diode Recovery Test Circuit and Waveforms(P-Channel)



Gate Charge Test Circuit and Waveform(P-Channel)



Customer Service

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